

•General Description

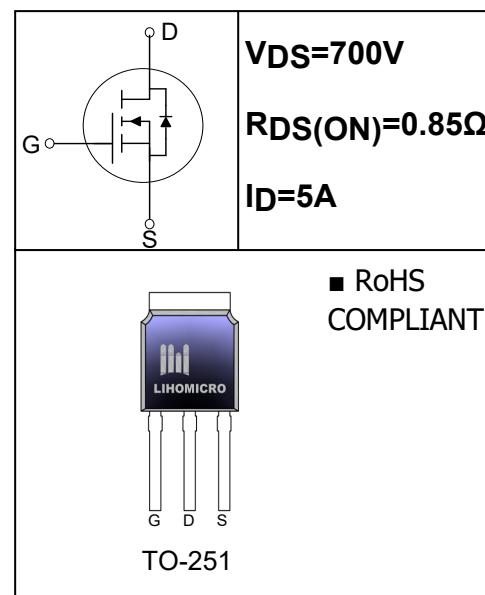
The SJ MOSFET LH70R850 has the low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device offers extremely fast and robust body diode, and is suitable for telecom and power supplies.

•Features

- Low Power Loss By High Speed Switching
- Low On-Resistance

•Application

- Lighting
- Solar/Renewable/UPS-Micro Inverter System
- Power Supplies



•Ordering Information:

Part number	LH70R850		
Package	TO-251		
Basic ordering unit (pcs)	4000		
Normal Package Material Ordering Code	LH70R850T1-TO251-TU		
Halogen Free Ordering Code	LH70R850T1-TO251-TU-HF		

•Absolute Maximum Ratings (TC = 25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage	BV _{DSS}	700	V
Gate-Source Voltage	V _{GS}	±30	V
Continuous Drain Current TC = 25°C TC = 100°C	I _D	5	A
		3	
Pulsed drain current (TC = 25°C, tp limited by Tjmax) ¹	I _D pulse	15	A
Single Pulse Avalanche Energy	I _{AR}	2.5	A
Single Pulse Avalanche Energy ²	E _{AS}	63	mJ
Power Dissipation(TC=25°C)	P _D	34	W
Operating Temperature and Storage Temperature Range	T _J /T _{STG}	-55~+150	°C
Reverse diode dv/dt ³	dv/dt	15	V/ns
Maximum diode commutation speed ³	di/dt	50	V/ns

•Electronic Characteristics($T_c=25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_{\text{D}} = 250\mu\text{A}$	700	--	--	V
Gate Threshold Voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}} = V_{\text{GS}}, I_{\text{D}} = 250\mu\text{A}$	2.0	--	4.0	V
Drain-source On Resistance ³	$R_{\text{DS(ON)}}$	$V_{\text{GS}} = 10\text{V}, I_{\text{D}} = 1.5\text{A}$	--	0.73	0.85	Ω
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}} = 650\text{V}, V_{\text{GS}} = 0\text{V}, T_j = 25^\circ\text{C}$	--	--	1	uA
		$V_{\text{DS}} = 650\text{V}, V_{\text{GS}} = 0\text{V}, T_j = 125^\circ\text{C}$	--	--	100	
Gate-Source Leakage Current	I_{GSS}	$V_{\text{GS}} = \pm 30\text{V}$	--	--	± 1	uA
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 400\text{V}$ $f = 1.0\text{MHz}$	--	384	--	pF
Output Capacitance	C_{oss}		--	439	--	
Reverse transfer Capacitance	C_{rss}		--	19	--	
Turn-on delay time	$T_{\text{d(on)}}$	$V_{\text{DD}} = 325\text{V}, I_{\text{D}} = 4.7\text{A}$ $R_{\text{G}} = 25\Omega$	--	13.5	--	ns
Turn -Off Delay Time	$T_{\text{d(off)}}$		--	56	--	
Rise time	T_{r}		--	24	--	
Fall time	T_{f}		--	23.3	--	
Total Gate Charge	Q_{g}	$I_{\text{D}} = 4.7\text{A}, V_{\text{DS}} = 520\text{V}$ $V_{\text{GS}} = 10\text{V}$	--	11	--	nC
Gate-to-Source Charge	Q_{gs}		--	4.4	--	
Gate-to-Drain Charge	Q_{gd}		--	2.6	--	

•Dynamic Characteristics($T_c=25^\circ\text{C}$, unless otherwise specified)

Continuous Diode Forward Current	I_{s}	--	--	--	5	A
Reverse Recovery Current ¹	I_{RRM}	--	--	--	15	A
Diode Forward Voltage	V_{SD}	$T_j = 25^\circ\text{C}, I_{\text{s}} = 4.7\text{A}$ $V_{\text{GS}} = 0\text{V}$	--	--	1.35	V
Reverse Recovery Time	t_{rr}	$V_{\text{DD}} = 100\text{V}, I_{\text{f}} = I_{\text{s}}$ $dI_{\text{f}}/dt = 100\text{A}/\mu\text{s}$	--	263	--	ns
Reverse Recovery Charge	Q_{rr}		--	1.9	--	uC

•Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	3.4	$^\circ\text{C/W}$
Thermal Resistance Junction-ambient	R_{thJA}	62	$^\circ\text{C/W}$

Notes:

1.Repetitive Rating: Pulse width limited by maximum junction temperature.

2. $I_{\text{AS}} = 2.5\text{A}$, $V_{\text{DD}} = 50\text{V}$, $R_{\text{G}} = 25\Omega$, Starting $T_j = 25^\circ\text{C}$

3. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$

- **Typical Characteristics** $T_J=25^\circ\text{C}$, unless otherwise noted

Figure 1. On Region Characteristics

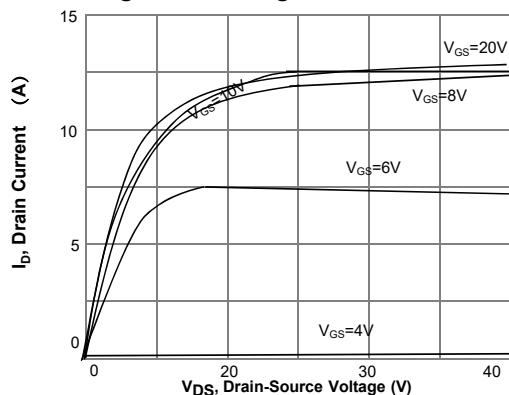


Figure 2. Transfer Characteristics

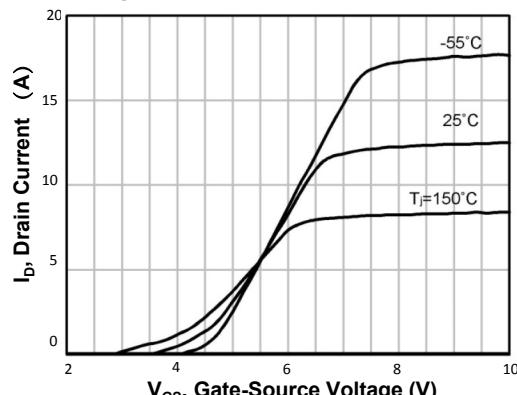


Figure 3. On Resistance Variation vs Drain Current and Gate Voltage

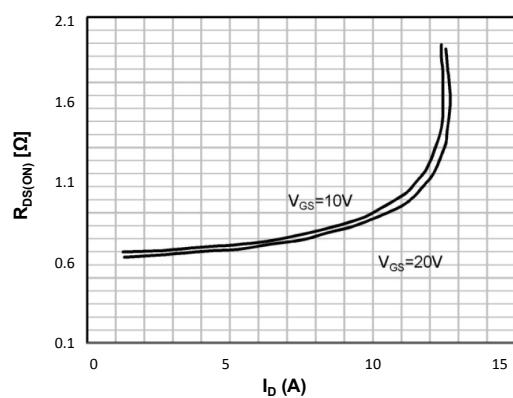


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

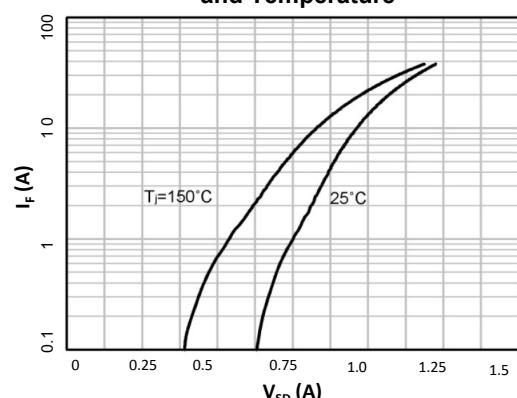


Figure 5. Capacitance Characteristics

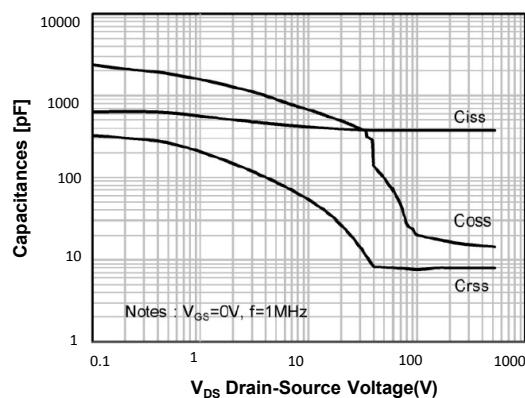
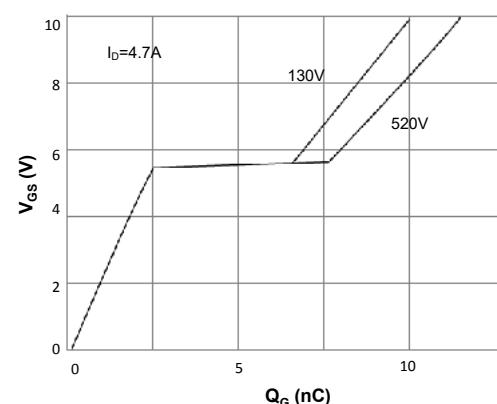
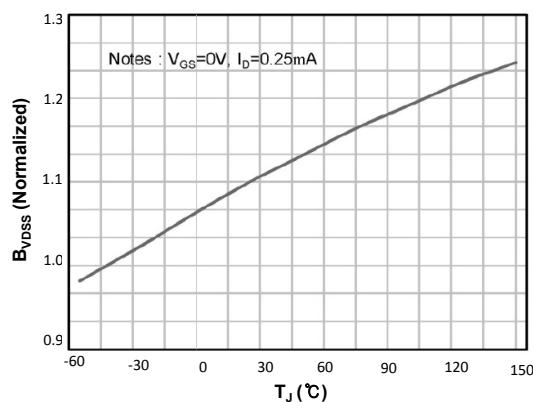
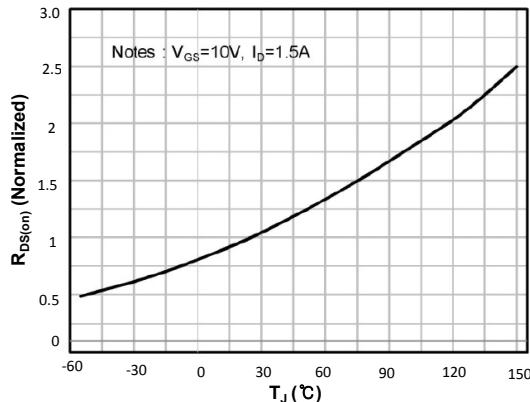
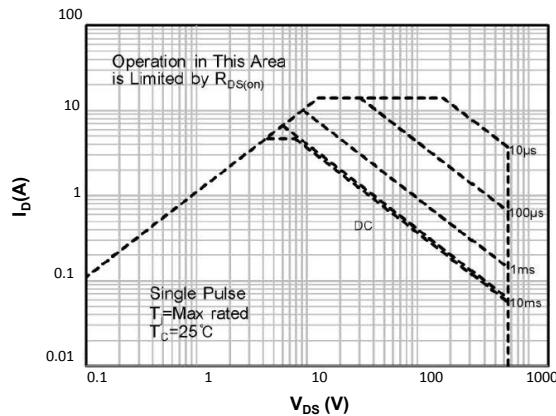
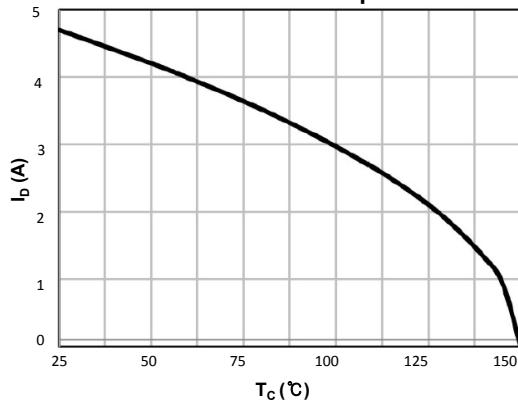
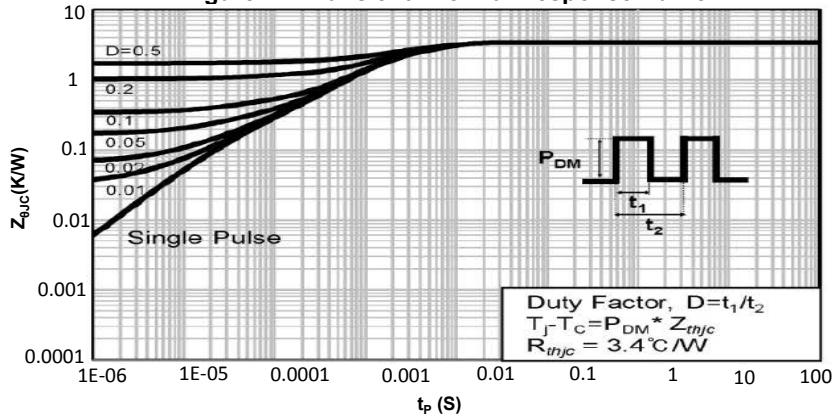


Figure 6. Gate Charge Characteristics



•Typical Characteristics (cont.)
Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature

Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

Figure 11. Transient Thermal Response Curve


- Test circuits&Waveforms

Fig 1. Gate Charge Test Circuit & Waveform

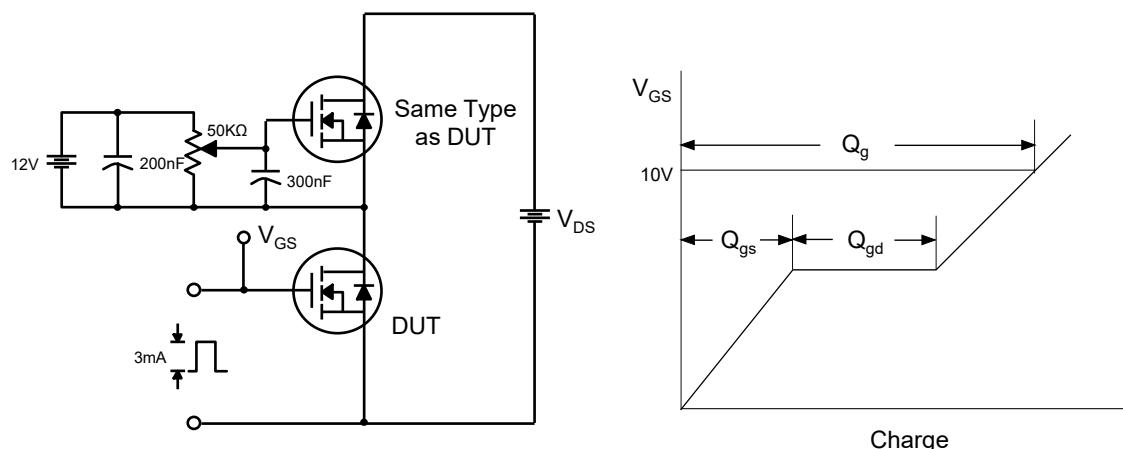


Fig 2. Resistive Switching Test Circuit & Waveforms

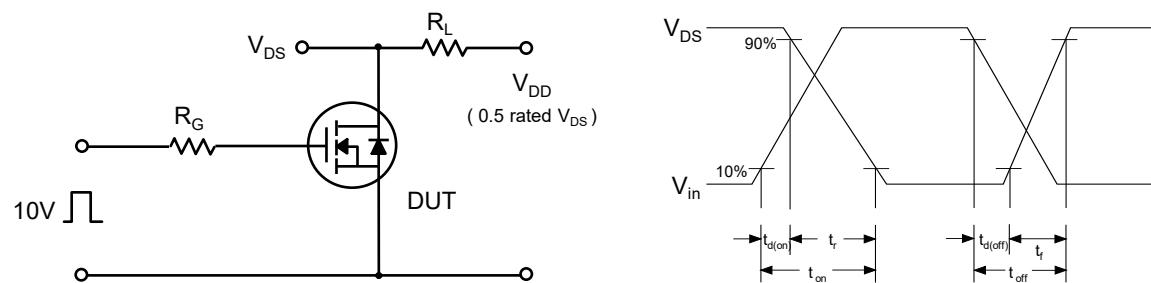
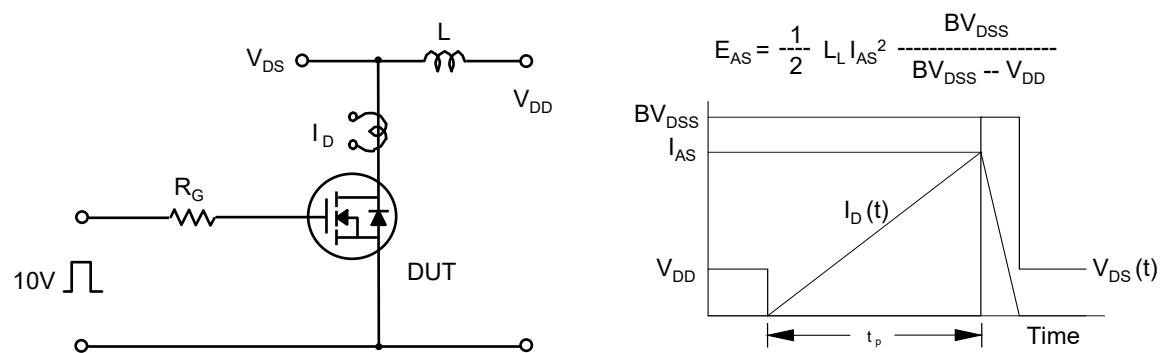
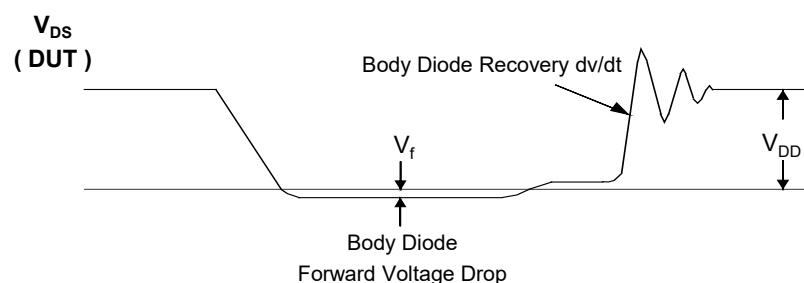
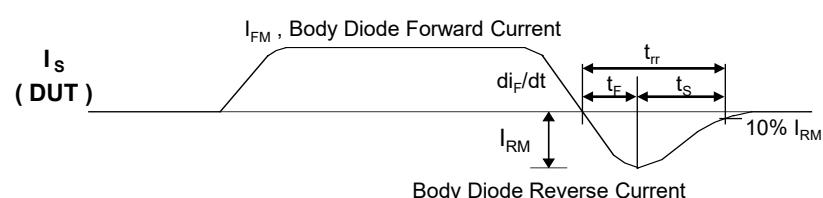
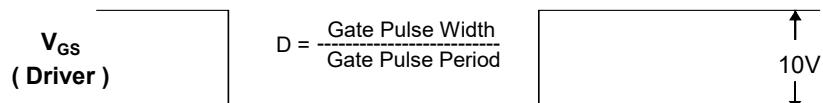
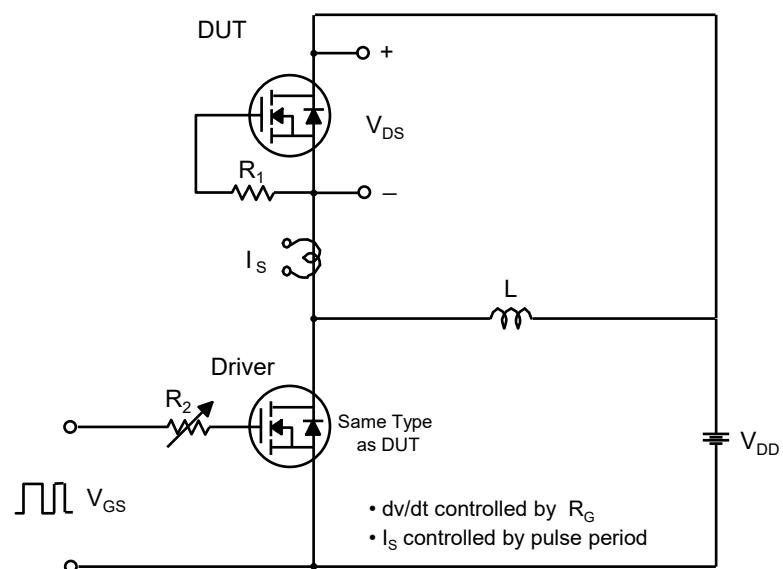


Fig 3. Unclamped Inductive Switching Test Circuit & Waveforms



- **Test circuits&Waveforms(cont.)**

Fig 4. Peak Diode Recovery dv/dt Test Circuit & Waveforms



•Dimensions (TO-251)

UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	2.10	2.50	B	0.80	1.30
b	0.50	0.90	C	0.40	0.70
b1	0.70	1.20	D1	5.10	5.60
b2	0.40	0.70	e1	2.10	2.45
D	6.20	6.80	e2	4.40	4.80
E	5.80	6.40			
L	3.60	9.80			
L1	0.80	1.60			

